

Измерение сопротивления тонкой пленки на поверхности электрода

M. A. Vorotyntsev^{1,2,3}, D. V. Konev³, M. Skompska⁴

¹ ICMUB-UMR 6302 CNRS, Universite de Bourgogne, Dijon, France

² M. V. Lomonosov Moscow State University, Russia

³ Institute for Problems of Chemical Physics, Chernogolovka, Russia

⁴ University of Warsaw, Poland

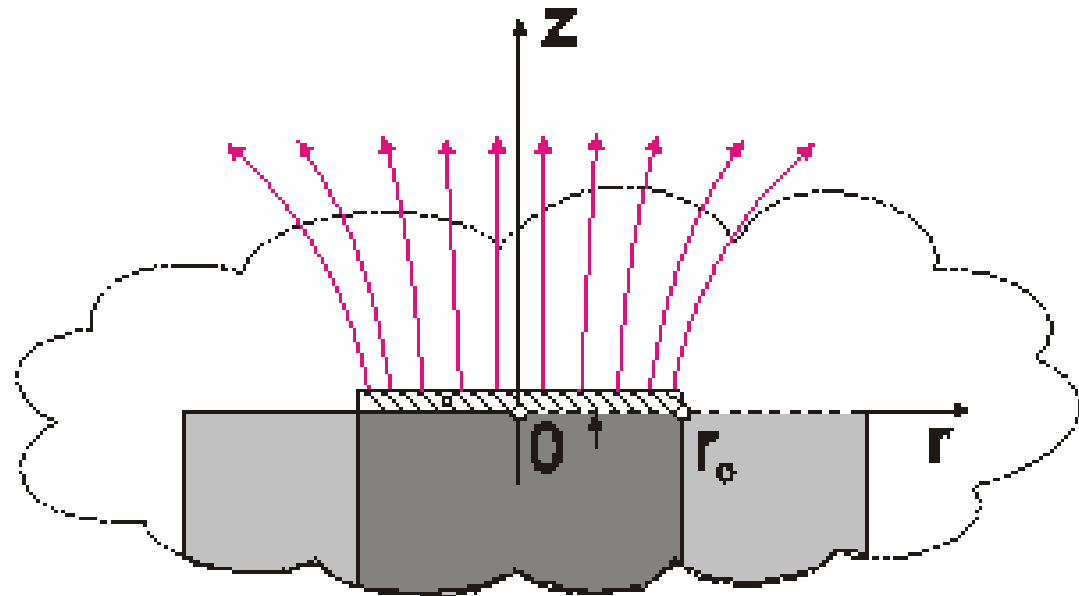
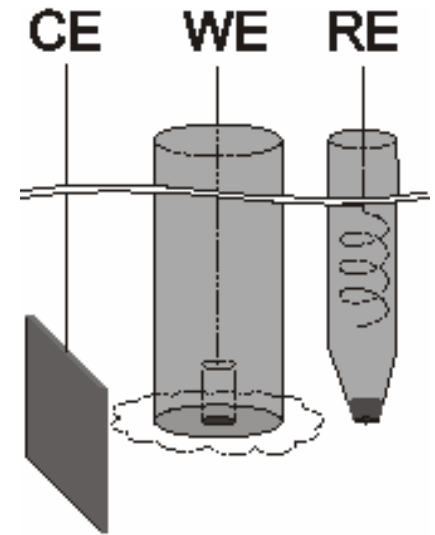
mivo2010@yandex.com, mv@elch.chem.msu.ru, mv@u-bourgogne.fr

In situ measurements of specific conductivity of films on electrode surface

Specific conductivity: function of potential

Impedance problems:

1. Special equipment
2. Interpretation (electrode/film resistance!)
3. Non-uniform electric field distribution

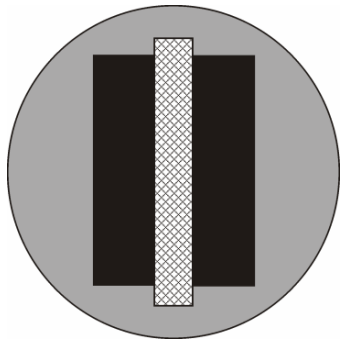


Principal in situ method: **microband electrodes**

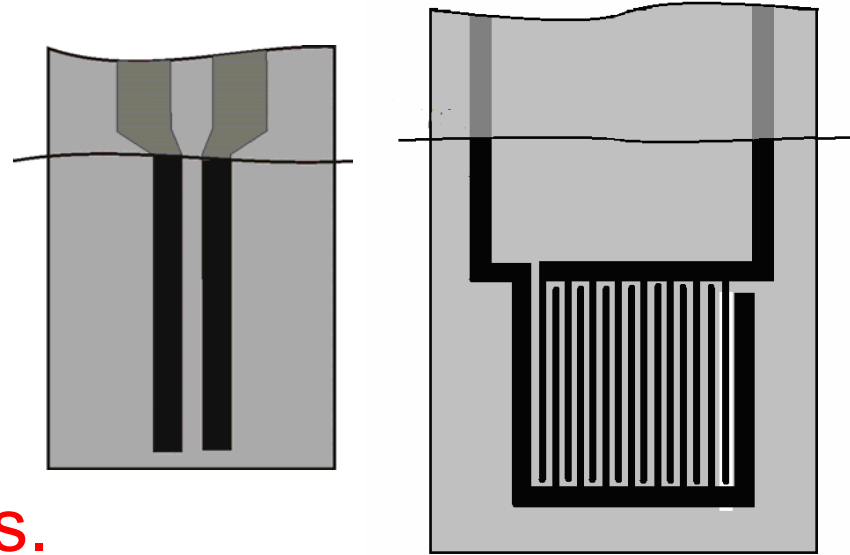
Various constructions (**no commercial supply!**):

2 metal plates separated by a thin insulating layer

One can clean by polishing



Lithographic metal layers:



Film above electrodes and gaps.

Current between them via film

Film resistance $\Delta U / I = R_f$ **Film conductivity:** $R_f = G / \kappa$

Film resistance: $\Delta U / I = R_f$ Film conductivity: $R_f = G / \kappa$

Problem of two electrodes configuration:

contribution of electrode/film resistance



4 microband electrodes: separation of R_f and $R_{m/f}$

U.Lange, V.M.Mirsky, *Analyt. Chim. Acta*, 2011, 687,105

Another problem: Is the film uniform? Which thickness?

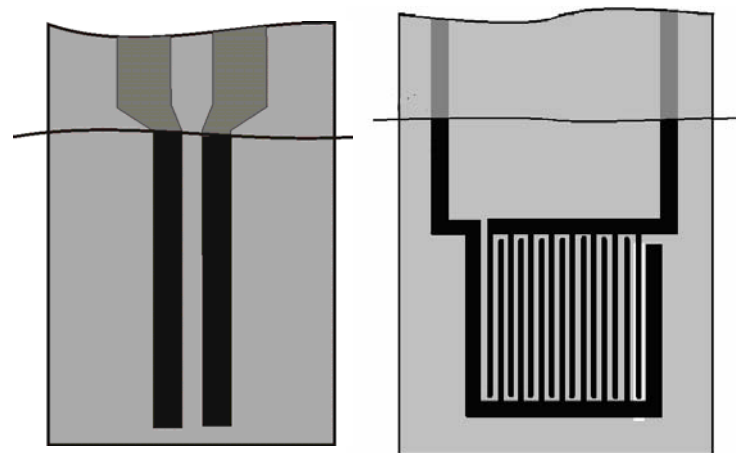
One opinion: only R_f

Another opinion: $G = L_g / A_f$

Gap width: 5-100 μm

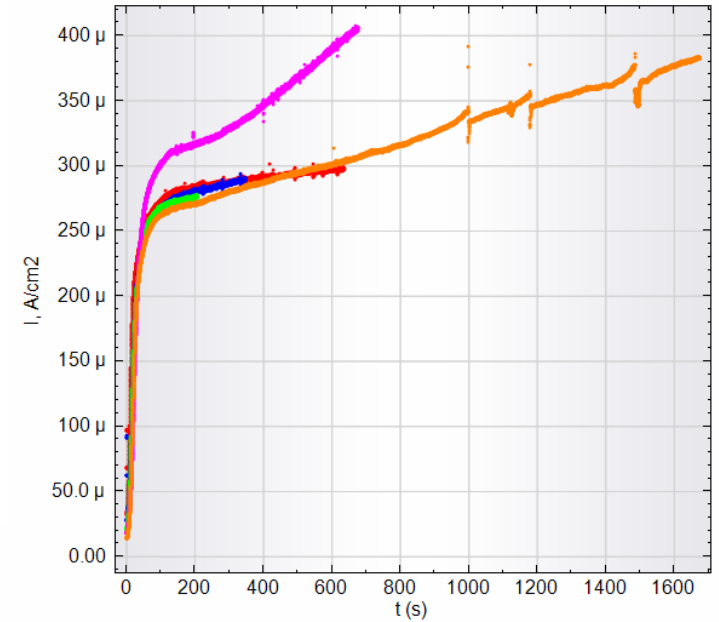
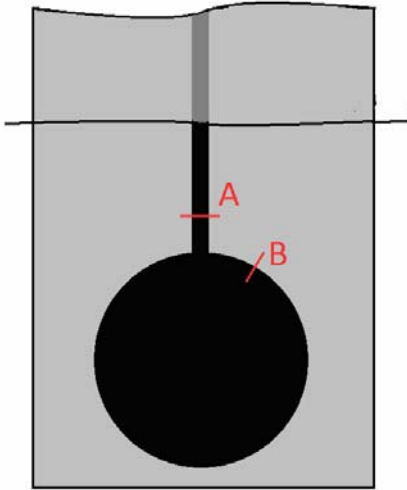
Film thickness?

Microband height?

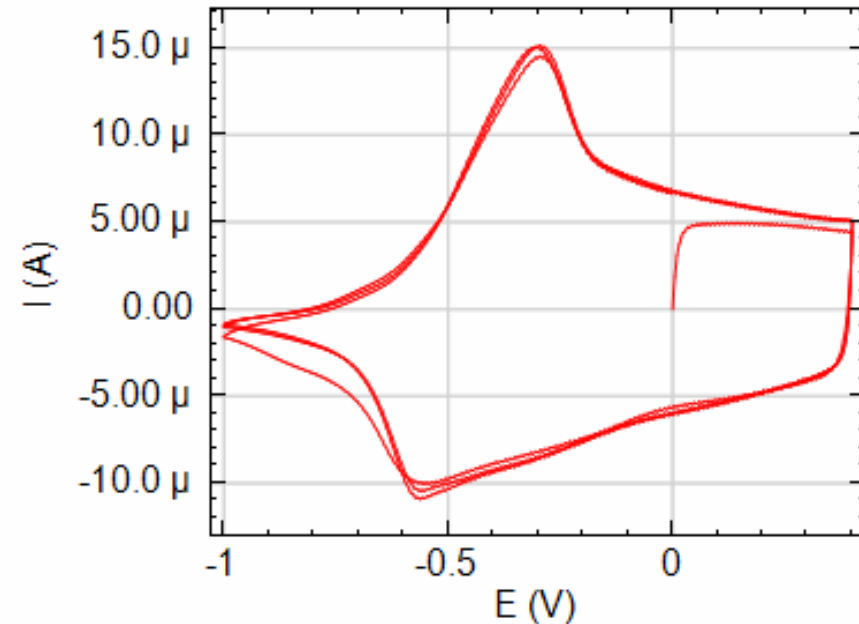


Our study: film growth on microband electrodes

Disk + single microband



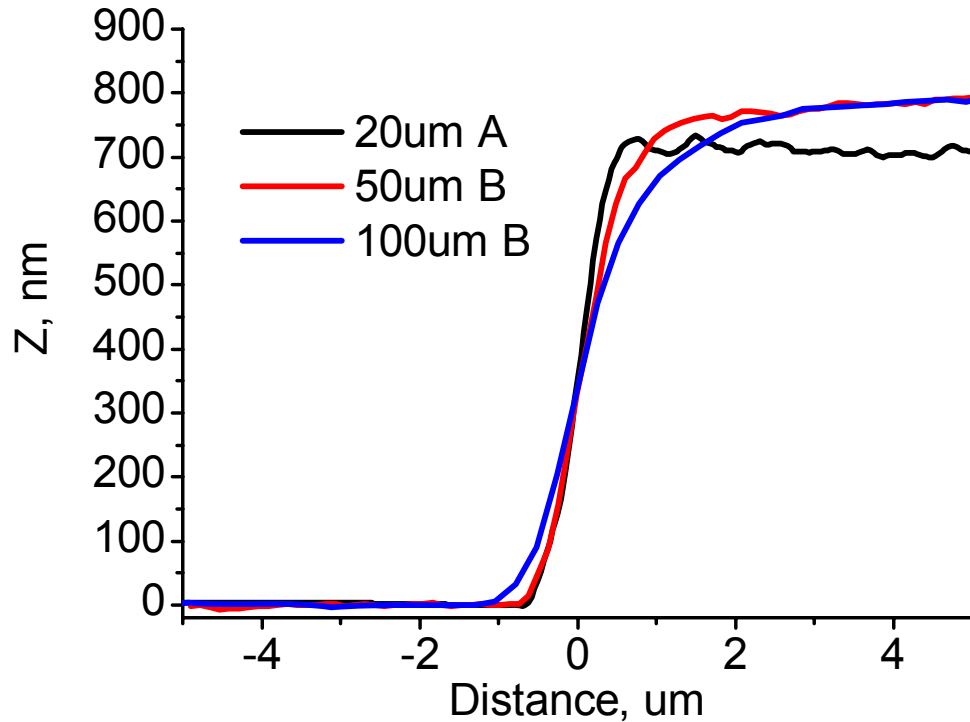
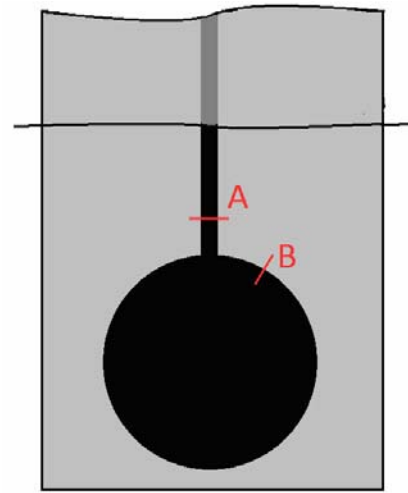
Series of pot-static depositions
various PPy film thicknesses



Disk + single microband

Large scale AFM device

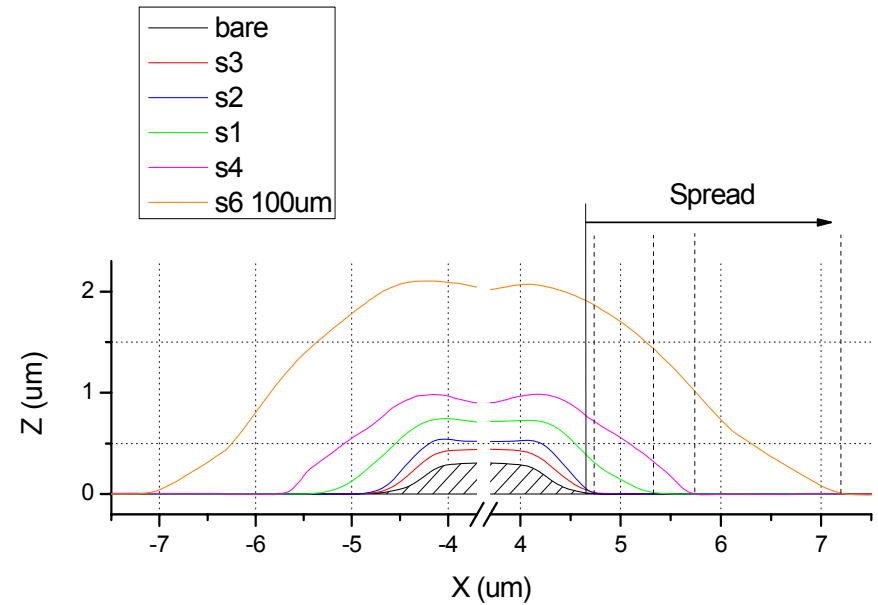
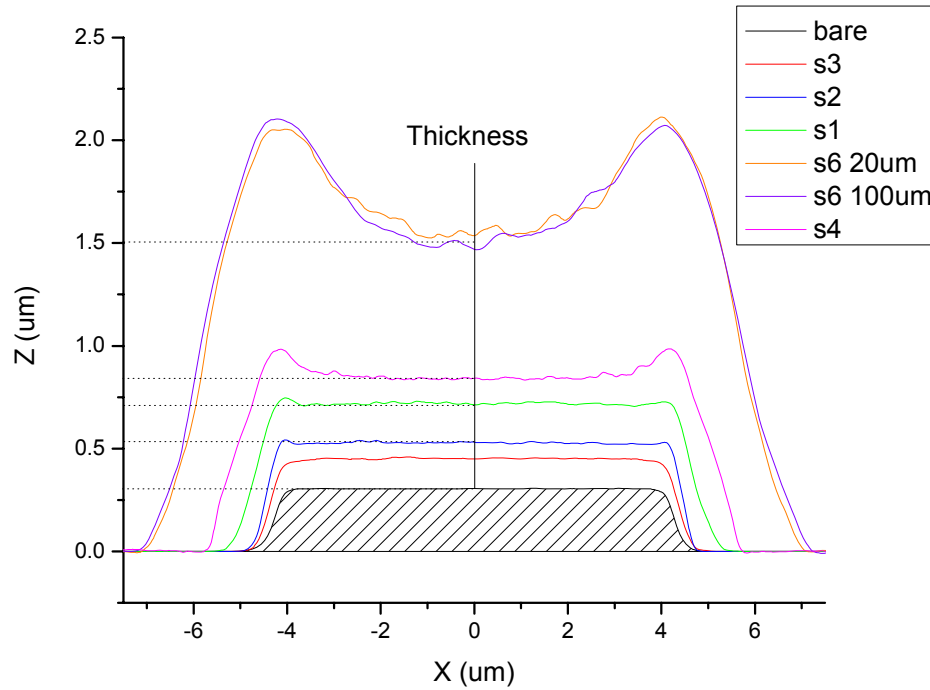
Contact mode



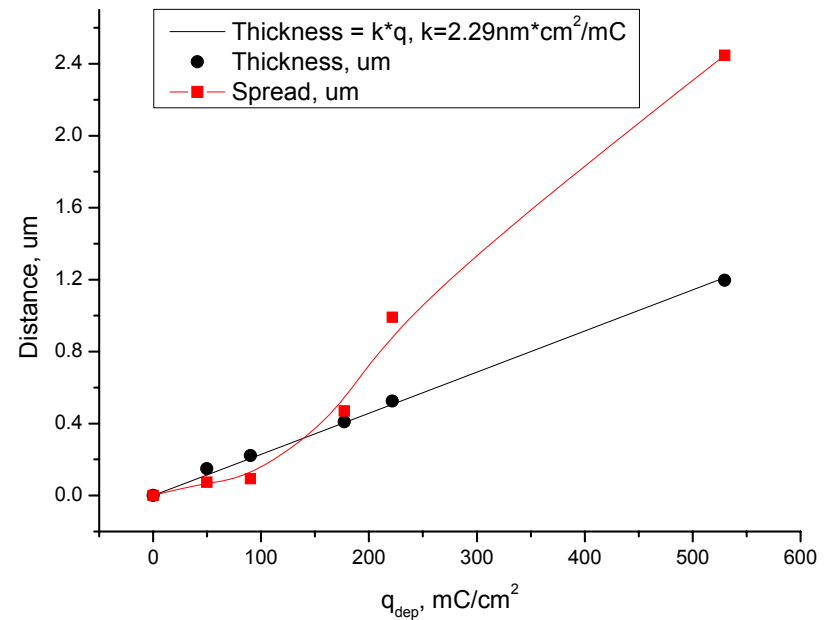
Similar profiles near edges of microband and macrodisk

Slightly different film thicknesses in central areas

Single microband: film cross-section



Growth rates in normal and tangent directions are comparable

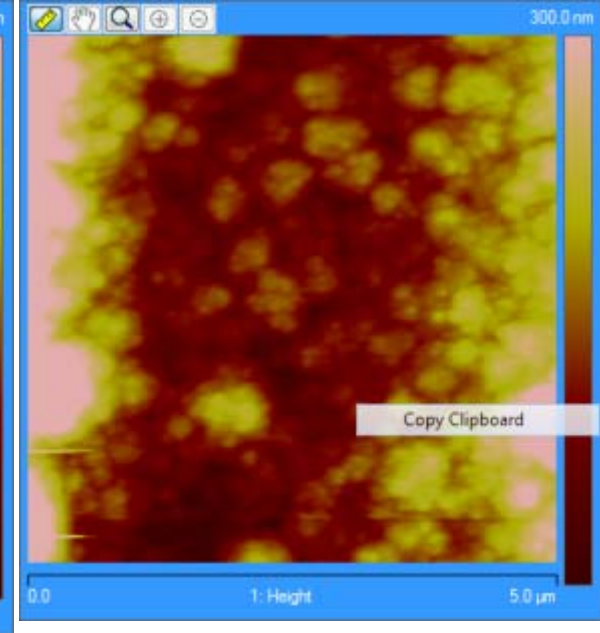
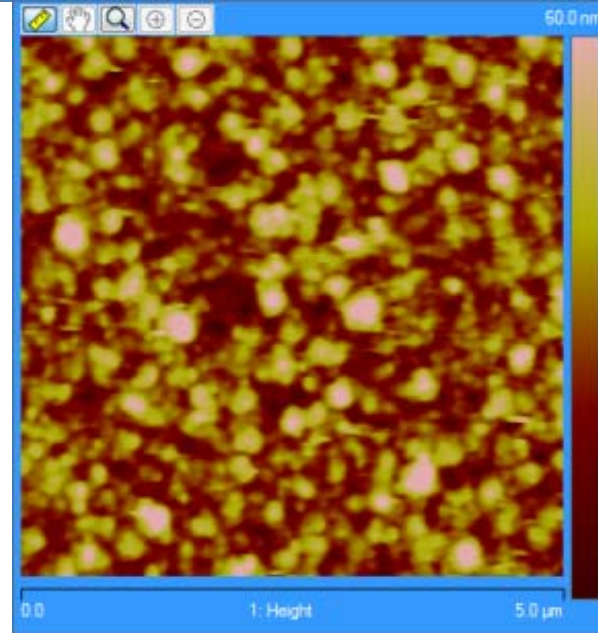
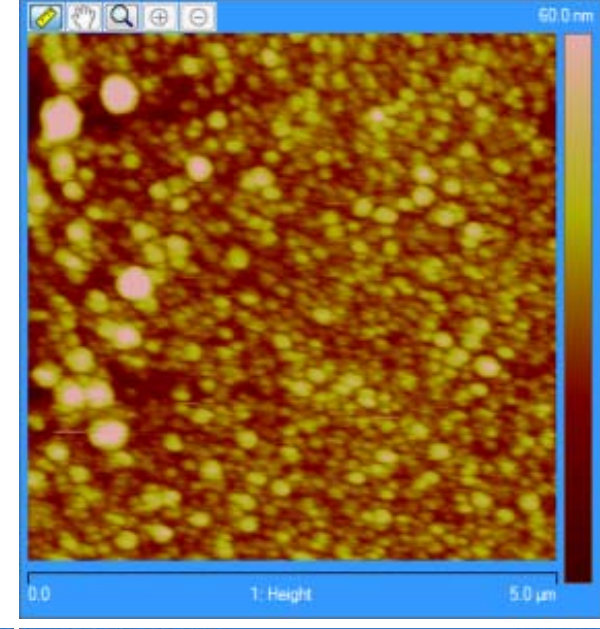
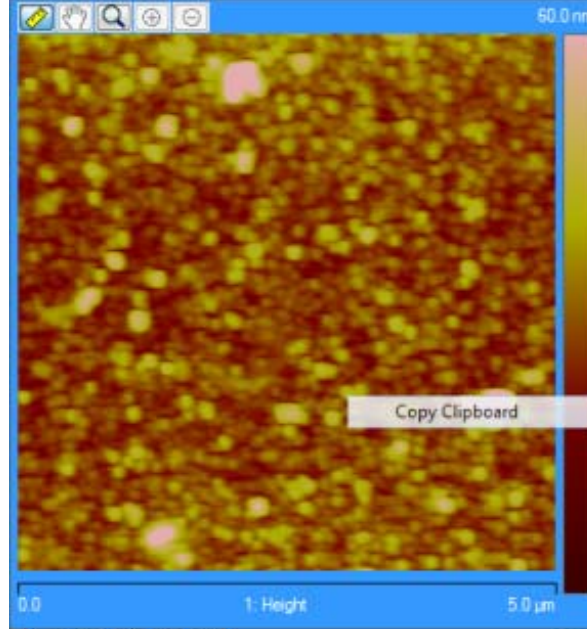


Disk: AFM images

Increase of film thickness:

Greater elements
Higher roughness

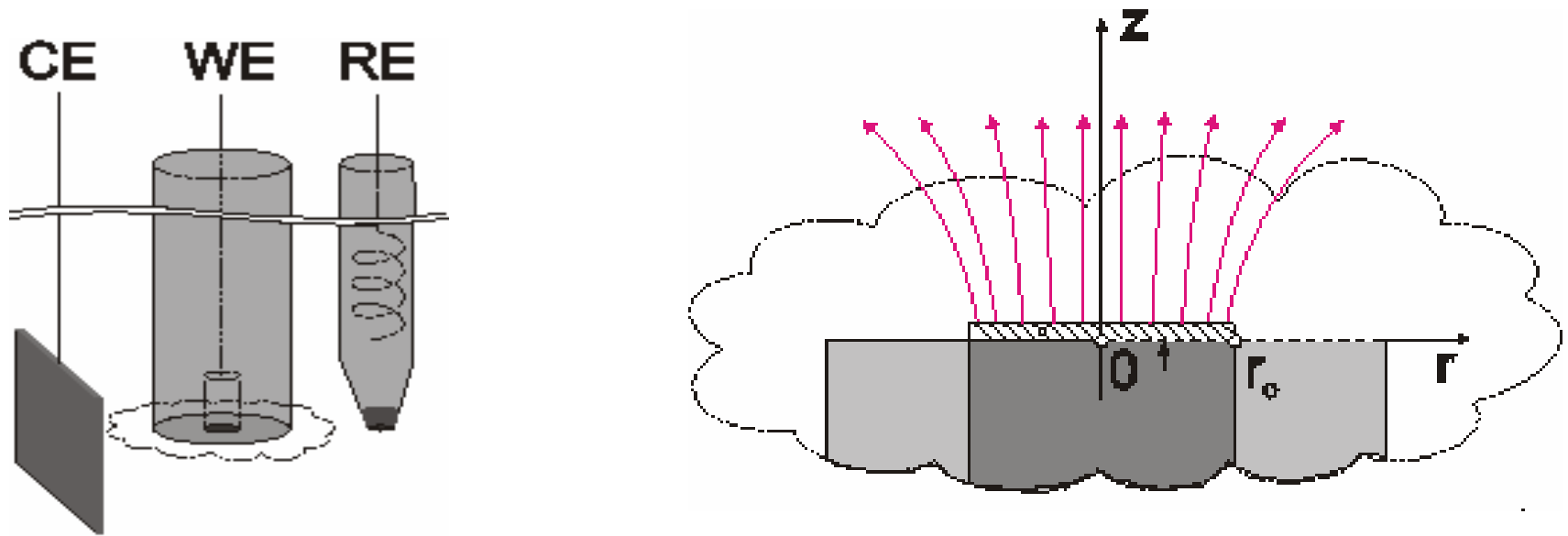
Impossible to estimate G , i.e. film conductivity κ



Film conductivity: novel method

M. A. Vorotyntsev, D. V. Konev,
Electrochim. Acta, 2011, 56, 9105

Standard 3-electrode cell with **static disc electrode**



Solution: **3D distribution**. Thin film: **1D distribution**

Film conductivity: novel method

Electrochim. Acta, 2011, 56, 9105

Potential step:

non-stationary potential/current distributions

Primary (short-time) potential/current distributions:

1) no concentration changes, 2) no changes at interfaces

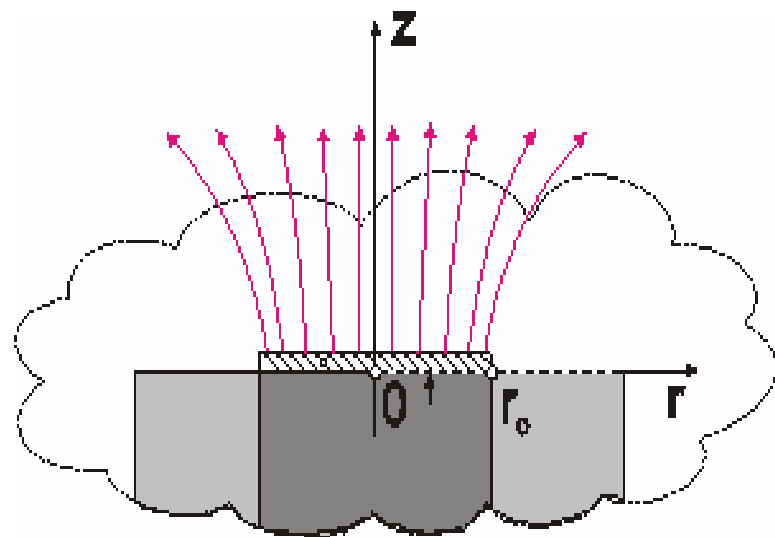
Only induced fluxes of mobile charges in solution & film

$$\Delta\Phi = 0 \quad \text{at } z > 0 \text{ (solution)}$$

$$\mathbf{i} = -\kappa_s \nabla\Phi \quad \text{at } z > 0 \text{ (solution)}$$

$$i_z \cong \kappa_f (V - \Phi_0) / L_f \text{ (thin film)}$$

V: amplitude of potential step



Total short-time resistance: $R_{\text{tot}} = V/I_o$

Nonadditive contributions of solution (R_s) and film (R_f) resistances

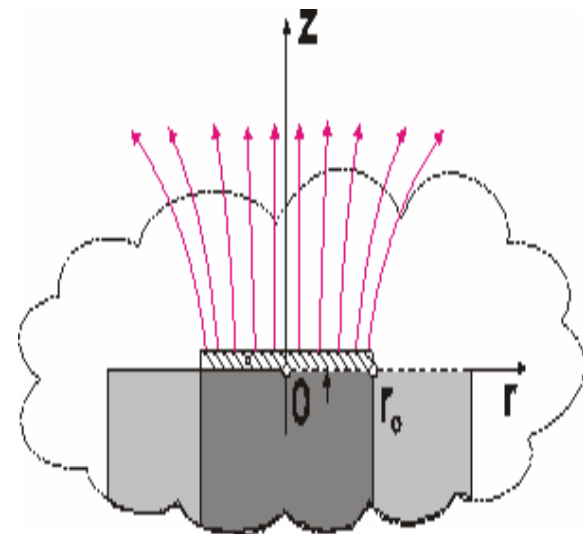
Analytical formulas:

$$R_{\text{tot}}(R_s, R_f) \text{ \& } R_f(R_s, R_{\text{tot}})$$

If R_{tot} is measured for a set of electrode potentials, $R_{\text{tot}}(E)$, one can determine $R_f(E)$

Specific conductivity of the film, $\kappa_f(E)$:

$$R_f = G_f / \kappa_f, \quad G_f = L_f / A_f, \quad A_f = \pi r_o^2$$



Conclusions

- For the first time: study of polymer **film growth on non-uniform surfaces** (single- and double-bands)
- Contrary to a widely-used hypothesis: **no preferential film propagation along the surface**
- To measure the interband current, i.e. film resistance the film thickness should be about a half of the interband gap, i.e. micrometer range, while **the local and global film morphologies become non-uniform**

Novel “potential-step method for disk electrode” to measure absolute values of **in situ** specific conductivity $\kappa_f(E)$ of film on electrode surface, i.e. in contact with solution under electrode potential control.

Advantages:

- Standard electrochemical cell,
- Measuring device = potentiostat (short-time signals),
- Normal-size (about mm) disk electrode, no need of micro/nanoelectrodes or larger-size (cm) electrodes,
- Standard film deposition procedure,
- Thin films (from a few tens of nm),
- Electronic or ionic or mixed (electron-ion) conductivity,
- Non-destructive type of measurement

Limitations of potential step method:

1) $R_f \ll R_s$, 2) too low conductivity (displacement current)

Combination of microband and potential step methods:

matching dependences resistance vs potential.

Another method to determine film conductivity, $\kappa(E)$